

Notice of References Cited

Application/Control No.

09/406,663

Applicant(s)/Patent Under
Reexamination
KNEBEL ET AL.

Examiner

Fred Ferris

Art Unit

2123

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-5,251,159	10-1993	Rowson, James A.	703/14
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Diagnosis and Characterization of Timing-Related Defects by Time-Dependent Light Emission", D. Knebel et al, International Test Conference, IEEE, October 1998
	V	"Failure Analysis of ULSI circuits Using Photon Emission", Y. Uraoka, IEEE Log Number 9211664, IEEE 1993
	W	"The Attack of the "Holey Shmoos": A Case Study of Advanced DFD and Picosecond Imaging Circuit Analysis (PICA)", W. Huott, ITC International Test Conference, IEEE, January 1999
	X	"An Integrated Photon Emission Microscope and MOSFET Characterization System of Combined Microscopic and Macroscopic Device Analysis", T.H. Ng, IEEE Proceedings for 7 th IPFA '99, August 1999

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	K	US-			
	L	US-			
	M	US-			

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	V	"Picosecond Imaging Circuit Analysis of the POWER3 Clock Distribution", P.N. Sandra, 1999 IEEE International Solid-State Conference, June 1999.
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